

[54] **IN-CIRCUIT TESTER CONSOLE**

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[73] Assignee: **Protech, Inc.,** San Antonio, Tex.

[\*\*] Term: **14 Years**

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[52] U.S. Cl. .... **D10/75**

[58] Field of Search ..... **D10/75, 80; D14/107,**  
**D14/114; 324/72, 72.5, 158 P, 158 F, 158 R,**  
**156, 500, 512, 519, 542, 555, 556**

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[57] **CLAIM**

The ornamental design for an in-circuit tester console, as shown.

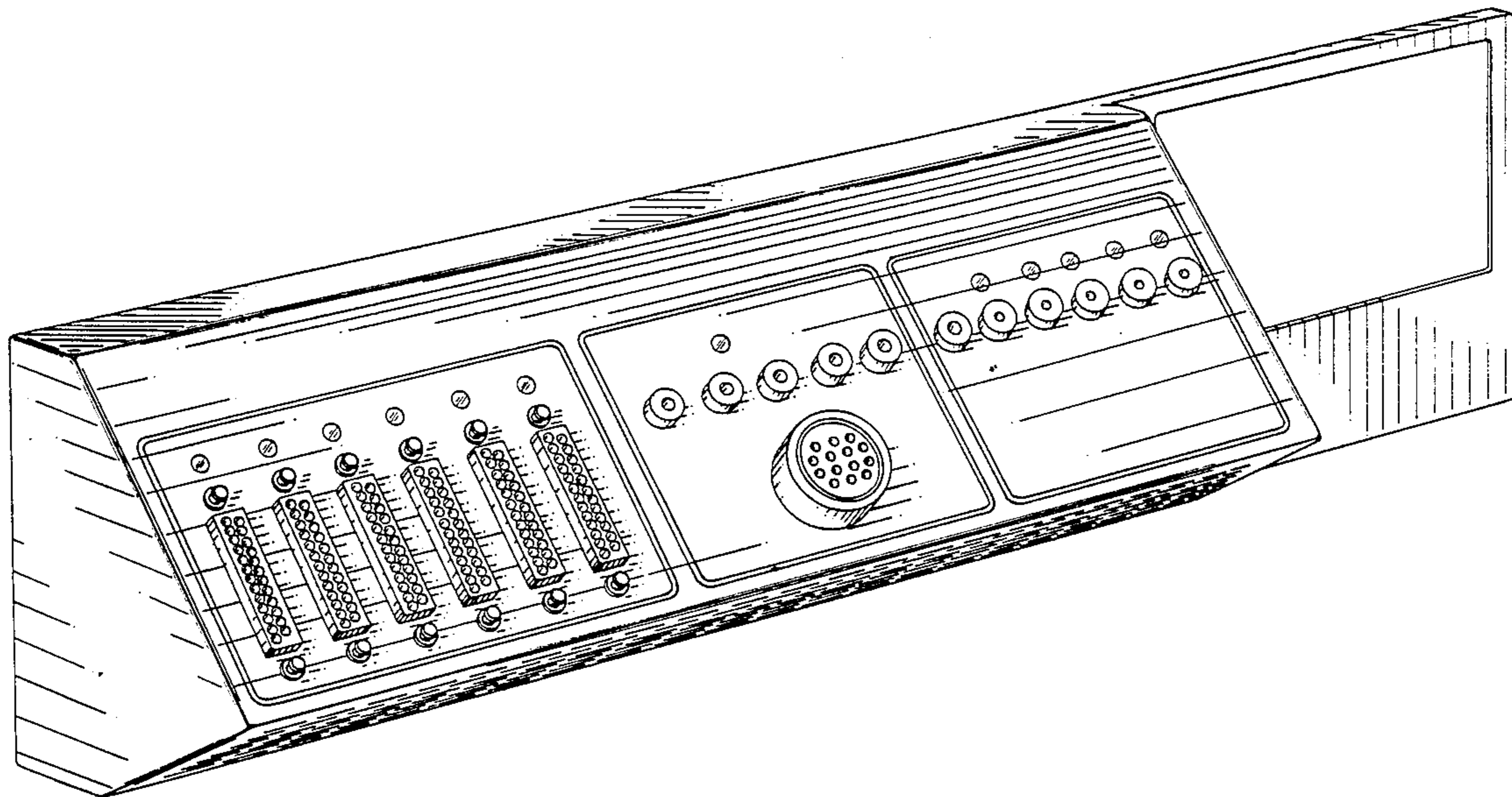
**DESCRIPTION**

FIG. 1 is a front elevational view of the in-circuit tester console showing our new design, the rear elevational view not shown being substantially plain and unornamented;  
 FIG. 2 is a right side elevational view;  
 FIG. 3 is a bottom plan view;  
 FIG. 4 is a left side elevational view;  
 FIG. 5 is a top plan view; and  
 FIG. 6 is a top, front, and left side perspective view thereof.

[56] **References Cited**

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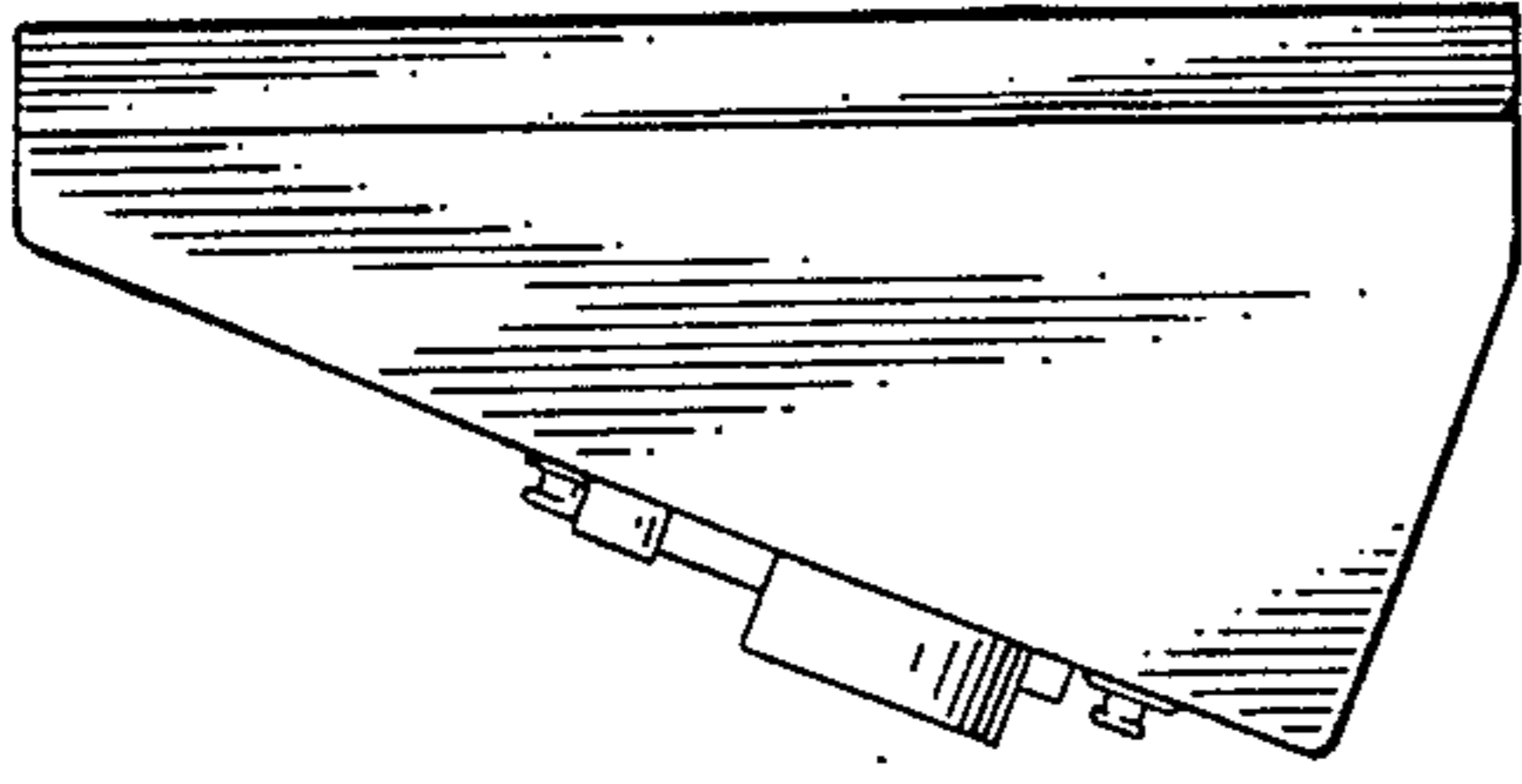


FIG. 2

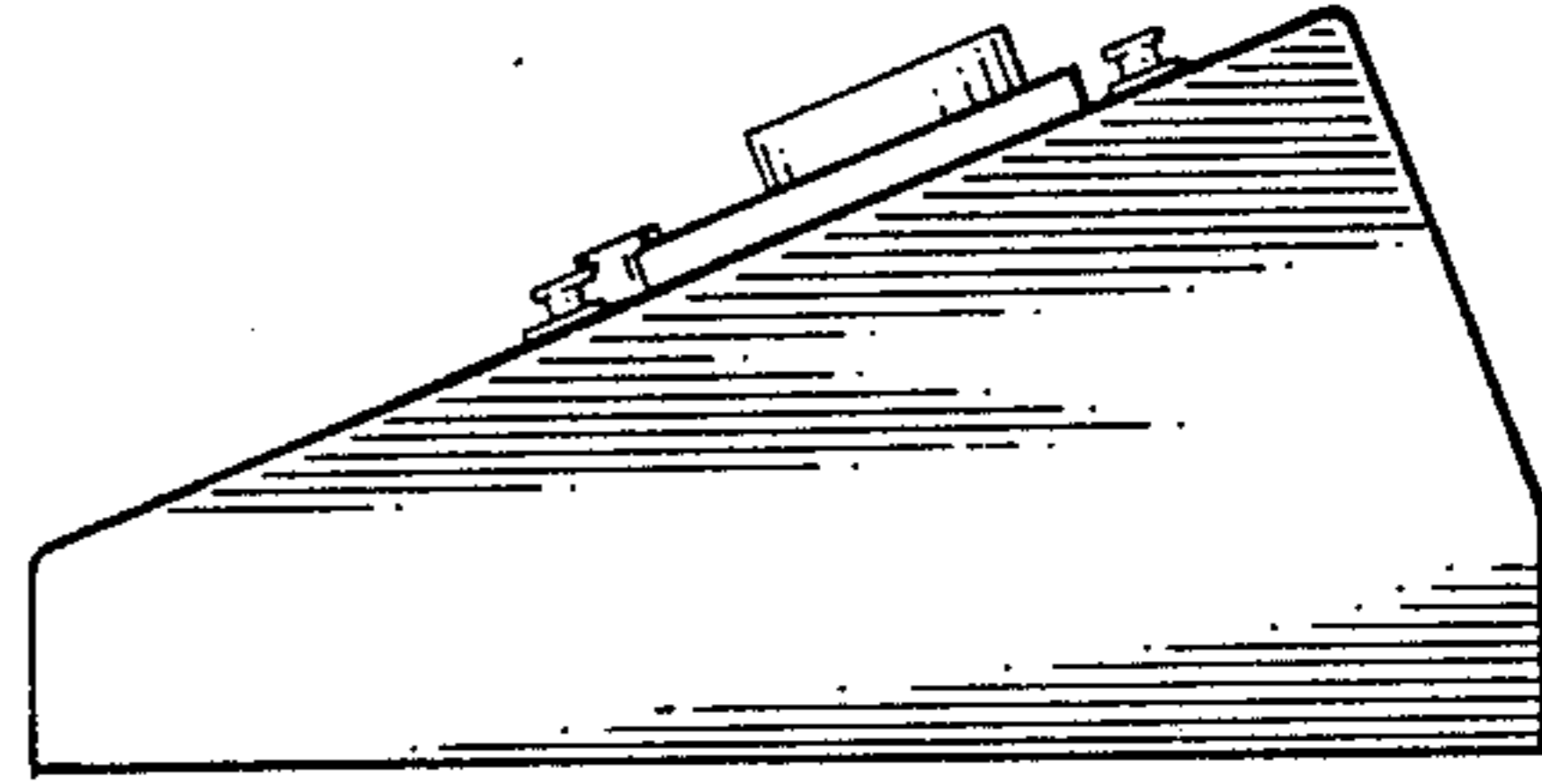


FIG. 4

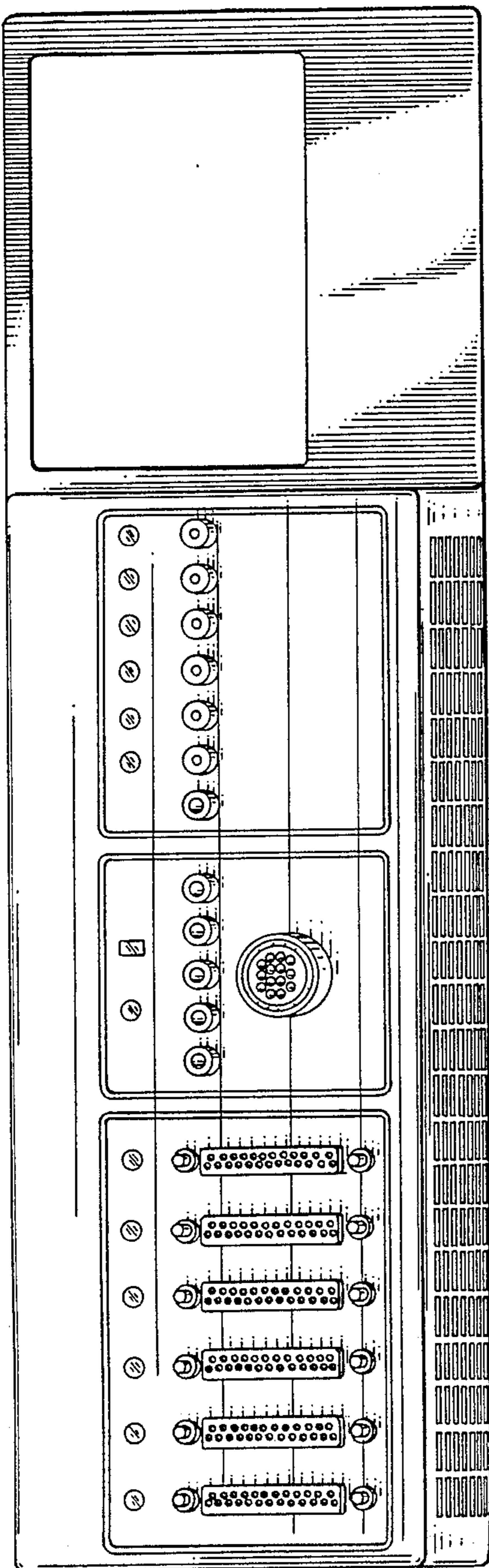


FIG. 1

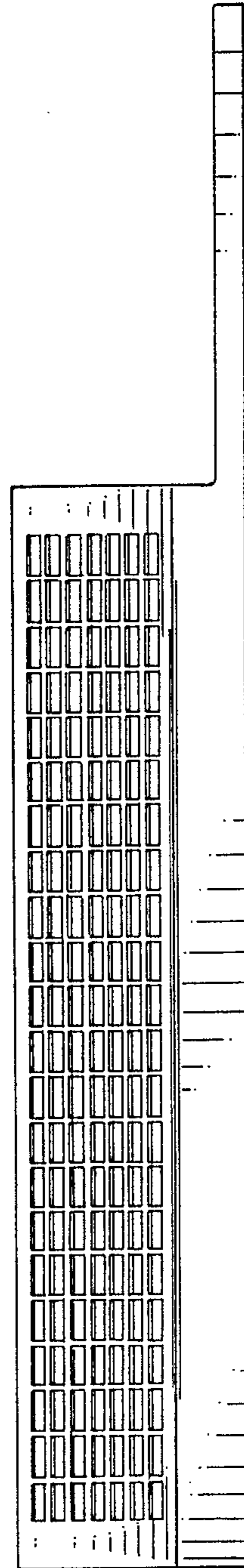


FIG. 3



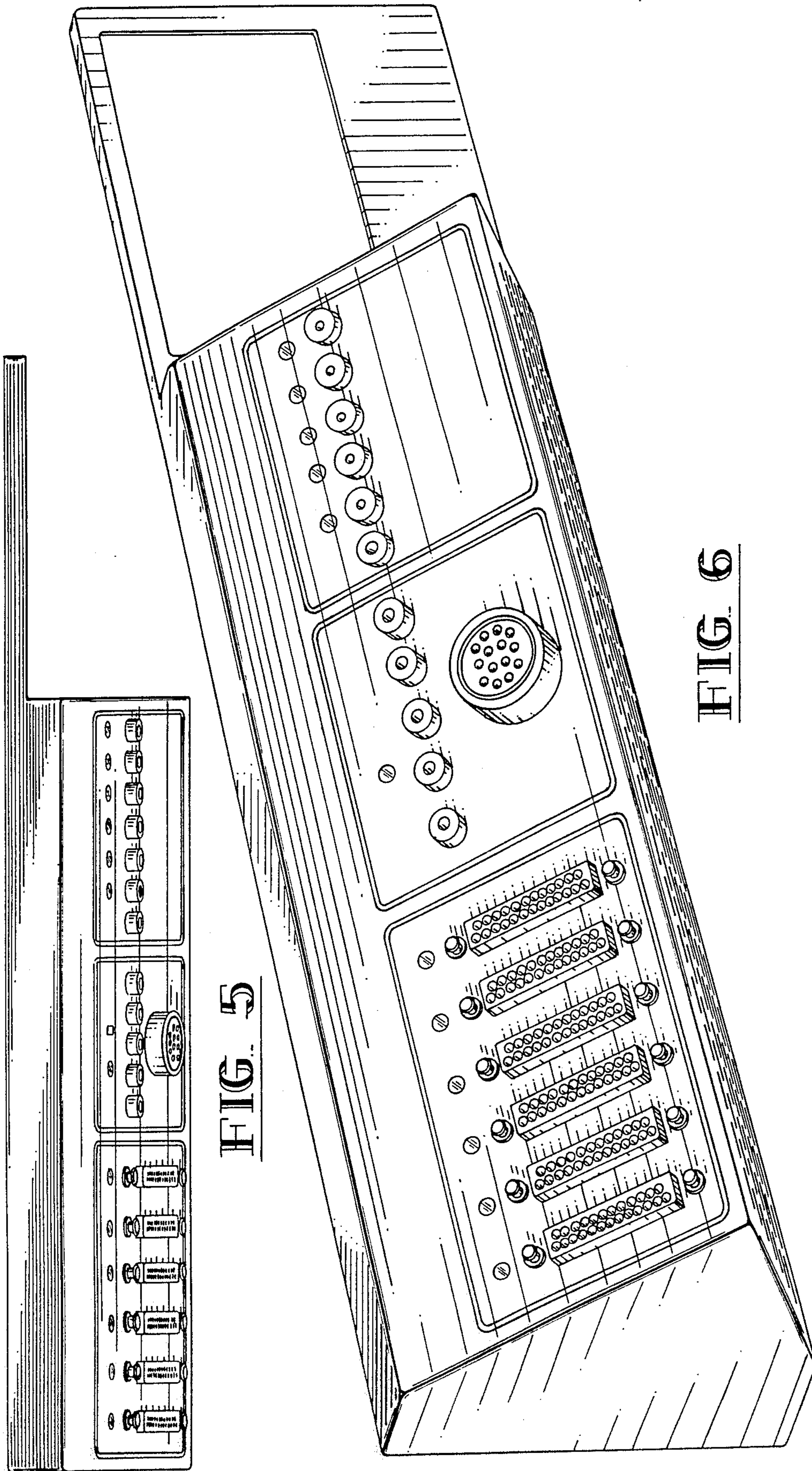


FIG. 5

FIG. 6